NX3DV42

Dual high-speed USB 2.0 double-pole double-throw analog switch

Rev. 3.1 — 20 October 2016

Product data sheet

1. General description

The NX3DV42 is a double-pole double-throw analog switch suitable for use as an analog or digital multiplexer/demultiplexer. Its wide bandwidth and low bit-to-bit skew allows the NX3DV42 to pass high-speed differential signals with good signal integrity. Its high channel to channel crosstalk rejection results in minimal noise interference. The bandwidth is wide enough to pass high-speed USB 2.0 differential signals (480 Mb/s). It consist of two switches, each with two independent input/outputs (HSDn+ and HSDn-) and a common input/output (D+ or D-). One digital input (S) is used to select the switch position. When pin $\overline{\text{OE}}$ is HIGH, the switches are turned off. Schmitt trigger action at the select input (S) and output enable input ($\overline{\text{OE}}$) makes the circuit tolerant to slower input rise and fall times across the entire V_{CC} range from 3.0 V to 4.3 V.

2. Features and benefits

- Supply voltage range from 3.0 V to 4.3 V
- 4 Ω typical ON resistance
- 7.3 pF typical ON capacitance
- 950 MHz typical bandwidth or data frequency
- Low crosstalk of -30 dB at 240 MHz
- Break-before-make switching
- ESD protection:
 - ◆ HBM JESD22-A114F Class 3A exceeds 4000 V
 - CDM AEC-Q100-011 revision B exceeds 1000 V
 - ◆ HBM exceeds 12000 V for power to GND protection
- Latch-up performance exceeds 100 mA per JESD 78 Class II Level A
- Specified from -40 °C to +125 °C

3. Applications

- Cell phone, PDA, digital camera and notebook
- LCD monitor, TV and set-top box



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4. Ordering information

Table 1. Ordering information

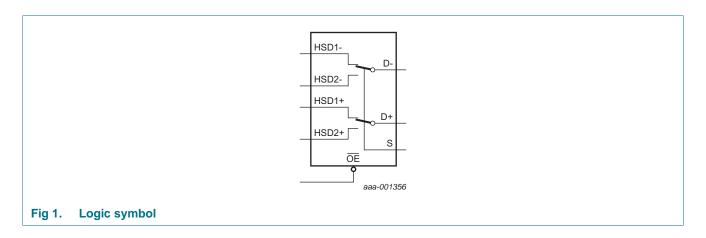
Type number	Package							
	Temperature range	Name	Description	Version				
NX3DV42GU	–40 °C to +125 °C	XQFN10	plastic, extremely thin quad flat package; no leads; 10 terminals; body 1.40 x 1.80 x 0.50 mm	SOT1160-1				
NX3DV42GU10	–40 °C to +125 °C	XQFN10	plastic extremely thin small outline package; no leads; 10 terminals; body 1.3 x 1.6 x 0.5 mm	SOT1337-1				
NX3DV42GU33	–40 °C to +125 °C	X2QFN10	plastic extremely thin small outline package; no leads; 10 terminals; body 1.3 x 1.6 x 0.33 mm	SOT1430-1				

5. Marking

Table 2. Marking

Type number	Marking code
NX3DV42GU	x4
NX3DV42GU10	x4
NX3DV42GU33	x4

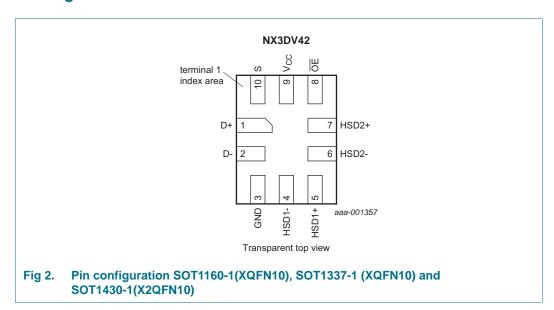
6. Functional diagram



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7. Pinning information

7.1 Pinning



7.2 Pin description

Table 3. Pin description

Symbol	SOT1160-1, SOT1337-1, SOT1430-1	Description
HSD1-, HSD2-	4, 6	independent input or output
HSD1+, HSD2+	5, 7	independent input or output
D+, D-	1, 2	common output or input
GND	3	ground (0 V)
ŌĒ	8	output enable input (active LOW)
S	10	select input
V _{CC}	9	supply voltage

8. Functional description

Table 4. Function table[1]

Input		Channel on
S	OE	
L	L	HSD1+ and HSD1-
Н	L	HSD2+ and HSD2-
X	Н	switch off

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care.

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9. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+5.5	V
VI	input voltage	pins S and OE	-0.5	+5.5	V
V_{SW}	switch voltage		-0.5	+5.5	V
I _{IK}	input clamping current	$V_{I} < -0.5 \text{ V}$	-50	-	mA
I _{SK}	switch clamping current	$V_1 < -0.5 \text{ V}$	-50	-	mA
I _{SW}	switch current		-	±100	mA
I _{CC}	supply current		-	+50	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C} \text{ to } +125 ^{\circ}\text{C}$	-	250	mW

^[1] The minimum input voltage rating may be exceeded if the input current rating is observed.

10. Recommended operating conditions

Table 6. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		3.0	4.3	V
VI	input voltage	pins S and OE	0	4.5	V
V_{SW}	switch voltage	<u>[1]</u>	0	V _{CC}	V
T _{amb}	ambient temperature		-40	+125	°C

^[1] To avoid sinking GND current from terminals D+ and D- when switch current flows in terminals HSDn+ and HSDn-, the voltage drop across the bidirectional switch must not exceed 0.4 V. If the switch current flows into terminals D+ and D-, no GND current will flow from terminals HSDn+ and HSDn-. In this case, there is no limit for the voltage drop across the switch.

^[2] For XQFN10 package: above 100 °C derate linearly with 4 mW/K.

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11. Static characteristics

Table 7. Static characteristics

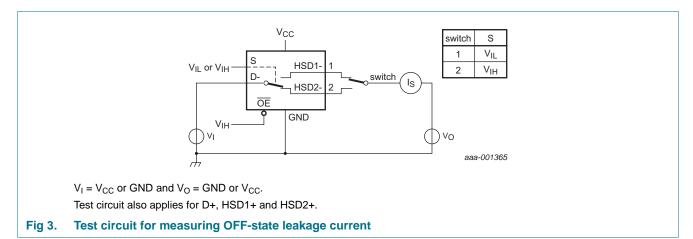
At recommended operating conditions; voltages are referenced to GND (ground 0 V).

Symbol	mbol Parameter Conditions		T _{amb} = -	-40 °C to	+85 °C	$T_{amb} = -40$ °	Unit	
			Min	Typ[1]	Max	Min	Max	
V _{IH}	HIGH-level	V _{CC} = 3.0 V to 3.6 V	1.3	-	-	1.3	-	V
	input voltage	V _{CC} = 4.3 V	1.7	-	-	1.7	-	V
V_{IL}	LOW-level	V _{CC} = 3.0 V to 3.6 V	-	-	0.5	-	0.5	V
	input voltage	V _{CC} = 4.3 V	-	-	0.7	-	0.7	V
V _{IK}	input clamping voltage	$V_{CC} = 3.0 \text{ V}; I_I = -18 \text{ mA}$	-	-	-1.2	-	-1.2	V
Iı	input leakage current	pins S and $\overline{\text{OE}}$; V _I = GND to 4.3 V; V _{CC} = 4.3 V; see Figure 4	-	-	±1	-	±10	μΑ
I _{S(OFF)}	OFF-state leakage current	V _{CC} = 4.3 V; see <u>Figure 3</u> and <u>Figure 6</u>	-	-	±1	-	±2	μΑ
I _{OFF}	power-off leakage current	V_I or $V_O = 0$ V to 4.3 V; $V_{CC} = 0$ V; see Figure 7	-	-	±1	-	±10	μА
I _{CC}	supply current	$V_I = V_{CC}$ or GND; $V_{CC} = 4.3 \text{ V}$; $V_{SW} = \text{GND or } V_{CC}$; see Figure 5	-	-	1	-	10	μΑ
ΔI_{CC}	additional supply current	$V_I = 2.6 \text{ V}; V_{CC} = 4.3 \text{ V};$ $V_{SW} = \text{GND or } V_{CC}$	-	-	10	-	10	μΑ
		$V_I = 1.8 \text{ V}; V_{CC} = 4.3 \text{ V};$ $V_{SW} = \text{GND or } V_{CC}$	-	-	15	-	15	μΑ
Cı	input capacitance	pins S and OE	-	1.0	-	-	-	pF
C _{S(OFF)}	OFF-state capacitance	pins HSDn+ and HSDn-; $V_{CC} = 3.3 \text{ V}; V_I = 0 \text{ V to } 3.3 \text{ V}$	-	2.8	-	-	-	pF
C _{S(ON)}	ON-state capacitance	pins D+ and D-; V_{CC} = 3.3 V; V_{I} = 0 V to 3.3 V	-	7.3	-	-	-	pF

^[1] Typical values are measured at T_{amb} = 25 $^{\circ}C$ and V_{CC} = 3.3 V.

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11.1 Test circuit and graphs



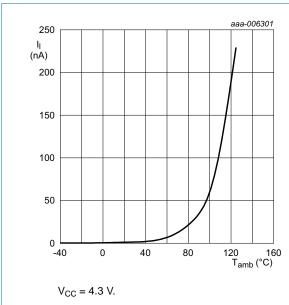
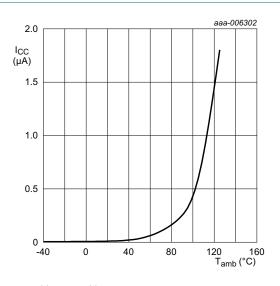


Fig 4. Waveform showing the typical input leakage current versus temperature



 V_{CC} = 4.3 V.

Fig 5. Waveform showing the typical supply current versus temperature

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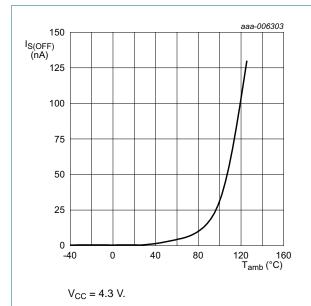


Fig 6. Waveform showing the typical OFF-state leakage current versus temperature

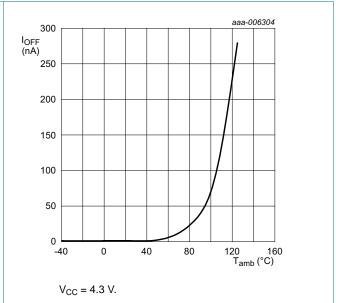


Fig 7. Waveform showing the typical power-off leakage current versus temperature

Dual high-speed USB 2.0 double-pole double-throw analog switch

11.2 ON resistance

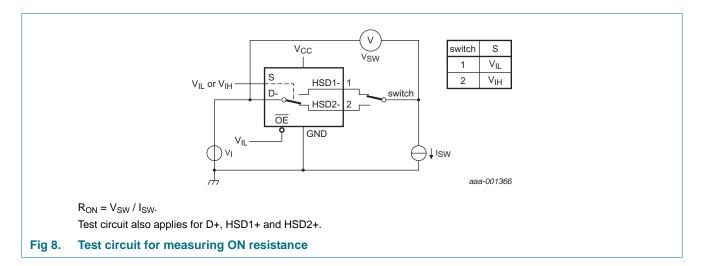
Table 8. ON resistance

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions $T_{amb} = -40 \text{ °C to } +85 \text{ °C}$		T _{amb} = -40 °	Unit			
			Min	Typ[1]	Max	Min	Max	
R _{ON}	ON resistance	$V_I = 0.4 \text{ V}; I_{SW} = 8 \text{ mA};$ see Figure 8						
		V _{CC} = 3.0 V	-	3.9	6.5	-	10	Ω
ΔR_{ON}		$V_1 = 0.4 \text{ V}; I_{SW} = 8 \text{ mA}$ [2]						
mismatch between channels	V _{CC} = 3.0 V	-	0.65	-	-	-	Ω	

- [1] Typical values are measured at T_{amb} = 25 °C.
- [2] Measured at identical V_{CC} , temperature and input voltage.

11.3 ON resistance test circuit



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12. Dynamic characteristics

Table 9. Dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for test circuit see Figure 12.

Symbol	Parameter	Conditions		$T_{amb} = -40 ^{\circ}\text{C} \text{ to } +85 ^{\circ}\text{C}$			$T_{amb} = -40$ °	Unit	
			M	lin	Typ[1]	Max	Min	Max	
t _{pd}	propagation delay	HSDn+ to D+ or HSDn- to D- or D+ to HSDn+ or D- to HSDn-; see Figure 9	3]						
		V _{CC} = 3.3 V		-	0.25	-	-	-	ns
t _{en}	enable time	S or OE to D+ or D-; see Figure 10	1]						
		V _{CC} = 3.0 V to 3.6 V		-	11.2	30	-	40	ns
t _{dis}	disable time	S or OE to D+ or D-; see Figure 10	<u>5]</u>						
		V _{CC} = 3.0 V to 3.6 V		-	3.9	25	-	30	ns
t _{b-m}	break-before-make	see Figure 11	3]						
	time	V _{CC} = 3.0 V to 3.6 V	2	.0	5.9	-	2.0	-	ns
t _{sk(p)}	pulse skew time	see Figure 9							
	V _{CC} = 3.0 V to 3.6 V	3]	-	20	-	-	-	ps	
t _{jit}	jitter time	$R_L = 50 \ \Omega$; $C_L = 5 \ pF$; t_r , t_f = 500 ps (10 % to 90 %) at 480 Mbs (PRBS = $2^{15} - 1$)	3]	-	200	-	-	-	ps

^[1] Typical values are measured at T_{amb} = 25 °C, C_L = 5 pF and V_{CC} = 3.3 V.

^[2] t_{pd} is the same as t_{PLH} and t_{PHL} .

^[3] Guaranteed by design.

^[4] t_{en} is the same as t_{PZH}.

^[5] t_{dis} is the same as t_{PHZ} .

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12.1 Waveforms and test circuits

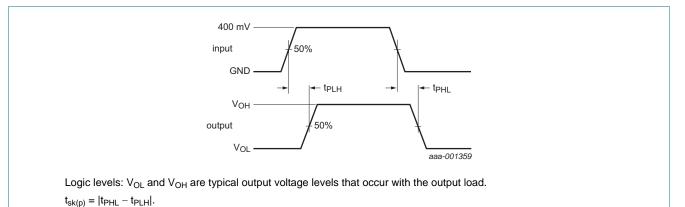


Fig 9. The data input to output propagation delay times and pulse skew time

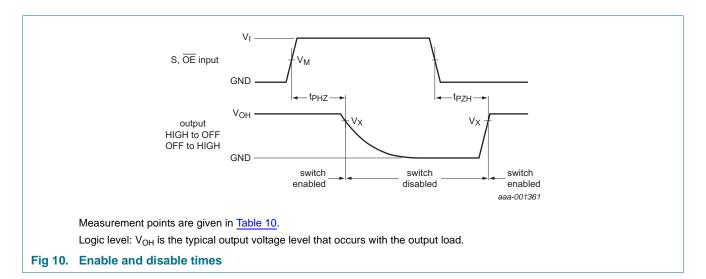
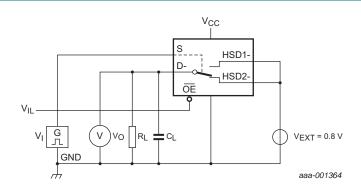


Table 10. Measurement points

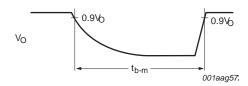
Supply voltage	Input	Output	
V _{CC}	V _M	V _I	V _X
3.0 V to 3.6 V	0.5V _{CC}	V _{CC}	0.9V _{OH}

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a. Test circuit.

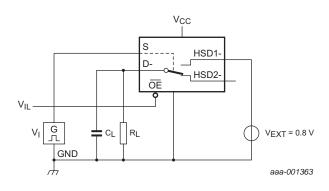




b. Input and output measurement points.

Test circuit also applies for D+, HSD1+ and HSD2+.

Fig 11. Test circuit for measuring break-before-make timing



Test circuit also applies for D+, HSD1+ and HSD2+.

Test data is given in Table 11.

Definitions test circuit:

R_L = Load resistance.

 C_L = Load capacitance including jig and probe capacitance.

 V_{EXT} = External voltage for measuring switching times.

 V_I may be connected to S or \overline{OE} .

Fig 12. Test circuit for measuring switching times

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Table 11. Test data

Supply voltage	Input L		Load		
V _{CC}	V _I	t _r , t _f	CL	R _L	
3.0 V to 3.6 V	V _{CC}	≤ 2.5 ns	5 pF	50 Ω	

12.2 Additional dynamic characteristics

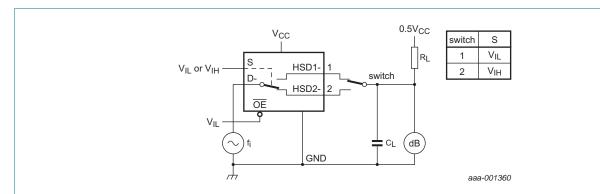
Table 12. Additional dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); $V_l = GND$ or V_{CC} (unless otherwise specified); $t_r = t_f < 2.5$ ns.

Symbol	Parameter	Conditions	Conditions		T _{amb} = 25 °C		
				Min	Typ[2]	Max	
f _(-3dB)	-3 dB frequency	$R_L = 50 \Omega$; see <u>Figure 13</u>	[1]		'		
response	$C_L = 0 \text{ pF}; V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$		-	950	-	MHz	
		$C_L = 5 \text{ pF}; V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$		-	450	-	MHz
$lpha_{iso}$	isolation (OFF-state)	f_i = 240 MHz; R_L = 50 Ω ; see Figure 14	<u>[1]</u>				
		V _{CC} = 3.0 V to 3.6 V		-	-30	-	dB
Xtalk	crosstalk	between switches; $f_i = 240$ MHz; $R_L = 50 \Omega$; see Figure 15	<u>[1]</u>				
		V _{CC} = 3.0 V to 3.6 V		-	-30	-	dB

^[1] f_i is biased at $0.5V_{CC}$.

12.3 Test circuits

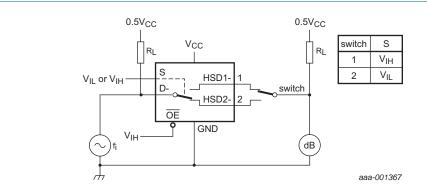


Adjust f_i voltage to obtain 0 dBm level at output. Increase f_i frequency until dB meter reads -3 dB. Test circuit also applies for D+, HSD1+ and HSD2+.

Fig 13. Test circuit for measuring the frequency response when channel is in ON-state

^[2] Typical values are measured at T_{amb} = 25 °C and V_{CC} = 3.3 V.

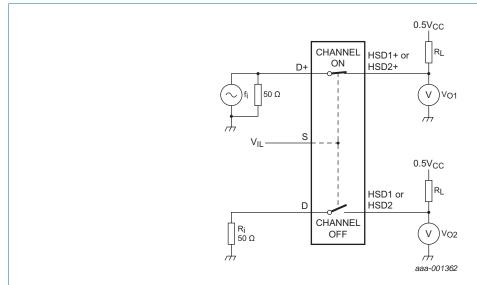
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Adjust fi voltage to obtain 0 dBm level at input.

Test circuit also applies for D+, HSD1+ and HSD2+.

Fig 14. Test circuit for measuring isolation (OFF-state)



20 $\log_{10} (V_{O2}/V_{O1})$ or 20 $\log_{10} (V_{O1}/V_{O2})$.

Fig 15. Test circuit for measuring crosstalk between switches

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13. Package outline

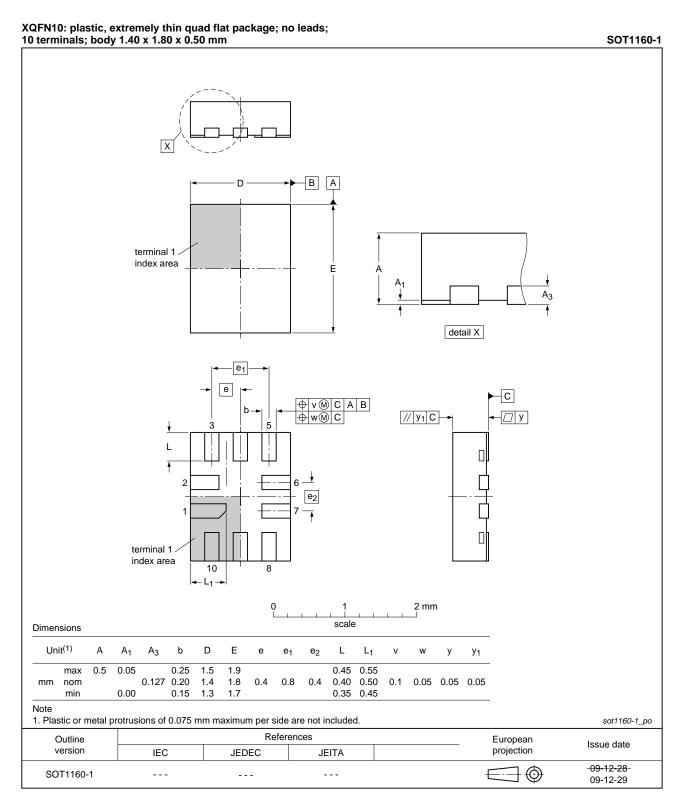


Fig 16. Package outline SOT1160-1 (XQFN10)

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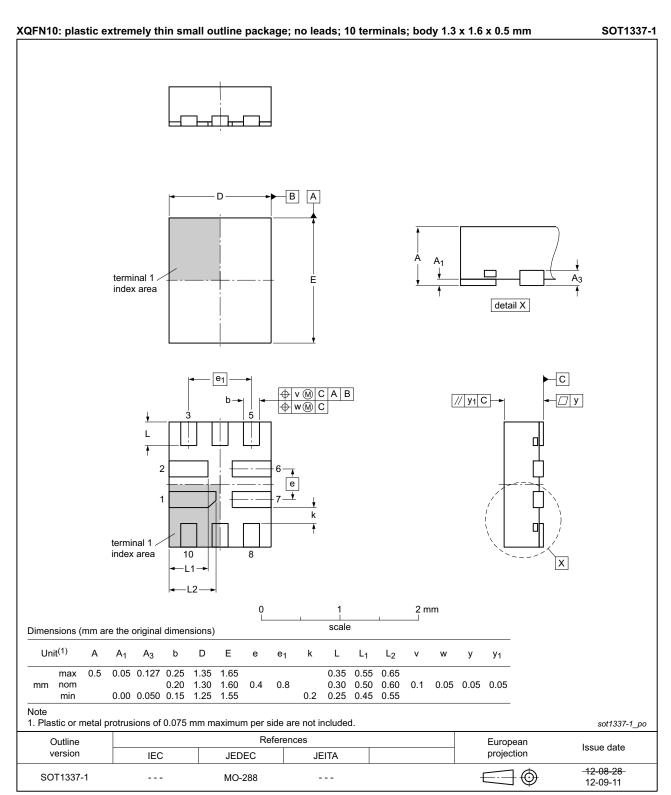


Fig 17. Package outline SOT1337-1 (XQFN10)

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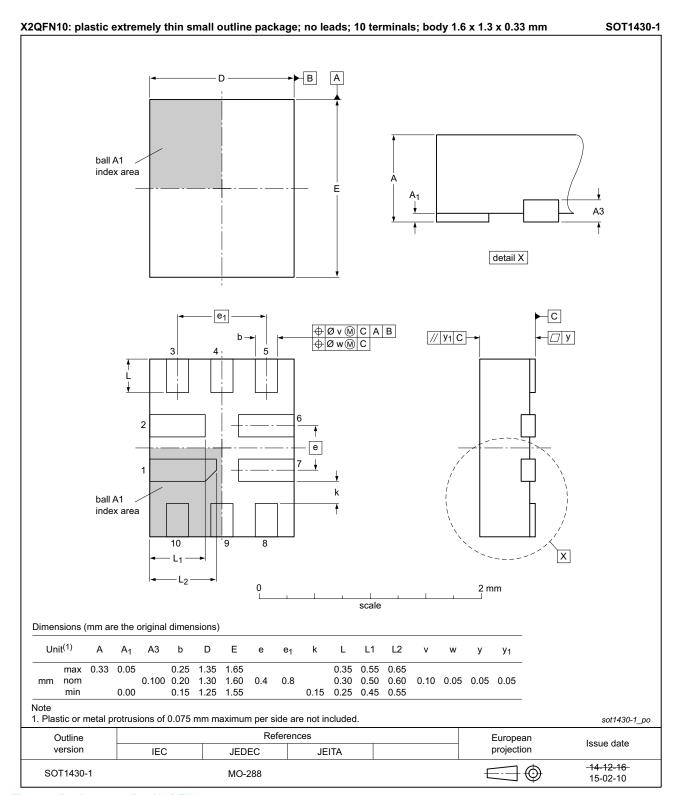


Fig 18. Package outline X2QFN10

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14. Abbreviations

Table 13. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal-Oxide Semiconductor
ESD	ElectroStatic Discharge
НВМ	Human Body Model
LCD	Liquid Crystal Display
MM	Machine Model
TTL	Transistor-Transistor Logic

15. Revision history

Table 14. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
NX3DV42 v.3.1	20161020	Product data sheet	-	NX3DV42 v.3	
Modifications:	Added NX3DV42GU33				
	Removed NX3DV42GM				
NX3DV42 v.3	20130213	Product data sheet	-	NX3DV42 v.2	
Modifications:	 Values added for T_{amb} = +125 °C throughout the data sheet. 				
	 Type number NX3DV42GU10 added (<u>Table 1</u>). 				
	 Marking code for type number NX3DV42GU10 added (<u>Table 2</u>). 				
	 Package outline drawing SOT1337-1 added (<u>Figure 17</u>). 				
NX3DV42 v.2	20120618	Product data sheet	-	NX3DV42 v.1	
Modifications:	 Package outline drawing SOT1049-2 changed to SOT1049-3 (Figure 17). 				
NX3DV42 v.1	20120103	Product data sheet	-	-	

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16. Legal information

16.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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NXP Semiconductors

Dual high-speed USB 2.0 double-pole double-throw analog switch

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